

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/583,201	HAUG, KARSTEN	
Examiner David S. Baker		Art Unit 2884	Page 1 of 1	

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	K	US-			
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	M	US-			

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	U	
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	W	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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